IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Date: September 28, 2001

Beaman et al.

Group Art Unit: 2858

Serial No.: 09/382,834

Examiner: V. Nguyen

Filed: August 25, 1999

Docket No.: YO993-028BX

HIGH DENSITY INTEGRATED CIRCUIT APPARATUS,

TEST PROBE AND METHODS OF USE THEREOF

Assistant Commissioner for Patents Washington, D. C. 20231

## CERTIFICATE OF FACSIMILE TRANSMISSION

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Dr. Daniel P. Morris, Esq.

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SUPPLEMENTARY AMENDMENT

In response to Office Action dated July 31, 2001, please consider the following:

## IN THE CLAIMS

53. (Added) A method according to claim 33 where each of said plurality of flexible contact elements have an original shape; the flexible contact elements deflect away from the original shape when said flexible contacts contact the electronic device; the

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